

Source	Background yield variation	Signal yield variation
Electron identification and isolation	2.7%	2.6%
Integrated luminosity	2.5%	2.5%
Jet energy scale	2.1–2.4%	0.1–0.3%
VV(V) tagging (heavy-flavour jets)	2.3%	2.0%
PDFs	1.0%	0.5%
Pileup	0.3–0.9%	0.7–1.3%
b tagging (light-flavour jets)	0.7–0.8%	<0.1%
Muon identification and isolation	0.5%	0.4%
Trigger efficiency	0.1–0.3%	0.1–0.3%
Jet energy resolution	0.2%	0.2%
	Affecting only $t\bar{t}$ (31.8% of the total bkg.)	
μ_R and μ_F scales	12.2–12.3%	
$t\bar{t}$ cross section	5.3%	
	Affecting only Drell–Yan (64.5% of the total bkg.)	
μ_R and μ_F scales	9.6%	
Drell–Yan cross section	4.9%	
Drell–Yan additional uncertainty	2.1–2.2%	
Simulated sample size	0.5–1.3%	
	Affecting only VV (1.1% of the total bkg.)	
μ_R and μ_F scales	4.3–4.8%	
	Affecting only signal	
μ_R and μ_F scales		1.8%